

FORM: PTO-1449 (REV: 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Atty Docket No: <b>92-0466.04</b>	Serial No:
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (37 CFR 1.98(b)) (use several sheets if necessary)		Applicant: <b>David A. Cathey</b>	
		Filing Date: <b>1/12/01</b>	Group:

**U.S. PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Name	Class	Subclass	
AK	AA	6,049,089	04/11/00	Cathey	257	010
AK	AB	5,786,659	07/28/98	Takagi et al.	313	309
AK	AC	5,662,815	09/02/97	Kim	216	011
AK	AD	5,583,393	12/10/96	Jones	313	495
AK	AE	5,532,177	07/02/96	Cathey	437	40
AK	AF	5,469,014	11/21/95	Itoh et al.	313	308
AK	AG	5,431,777	07/11/95	Austin et al.	156	622.1
AK	AH	5,378,658	01/03/95	Toyoda et al.	437	228
AK	AI	5,372,973	12/13/94	Doan et al.	437	228
AK	AJ	5,358,908	10/25/94	Reinberg et al.	437	228
AK	AK	5,330,920	07/19/94	Soleimani et al.	437	24
AK	AL	5,315,126	05/24/94	Field	257	010
AK	AM	5,269,877	12/14/93	Bol	156	628
AK	AN	5,201,992	04/13/93	Marcus et al.	156	643
AK	AO	5,138,220	08/11/92	Kirkpatrick	313	309
AK	AP	5,090,932	02/25/92	Dieumegard et al.	445	24
AK	AQ	5,063,327	11/05/91	Brodie et al.	313	482
AK	AR	4,968,382	11/06/90	Jacobson et al.	156	643
AK	AS	4,964,946	10/23/90	Gray et al.	156	643

**FOREIGN PATENT DOCUMENTS**

FOREIGN PATENT DOCUMENTS								
Examiner Initial	Document Number		Date	Country	Class	Subclass	Translation	
							Yes	No
AK	CA	3-238729	10/24/91	Japan	H01J9	02	<input checked="" type="checkbox"/>	<input type="checkbox"/>
	CB	57-43412	03/11/82	Japan	H01L21	205	<input checked="" type="checkbox"/>	<input type="checkbox"/>

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**OTHER ART** (including author, title, date, pertinent pages, etc.)

AK	DA		Hunt, Charles E., Johann T. Trujillo, William J. Orvis, "Structure and Electrical Characteristics of Silicon Field-Emission Microelectronic Devices," IEEE Transactions on Electron Devices, Vol. 38, No. 10, October 1991.
AK	DB		Marcus, R. B., T. S. Ravi, T. Gmitter, H. H. Busta, J. T. Niccum, K. K. Chin, and D. Liu, "Atomically Sharp Silicon and Metal Field Emitters," IEEE Transactions on Electron Devices, Vol. 38, No. 10, October 1991.
AK	DC		Wolf, Stanley, SILICON PROCESSING FOR THE VLSI ERA, Volume 2: Process Integration, Lattice Press, Sunset Beach, California, pp. 20-27, 1990.
AK	DD		Jones, G. W. and C. T. Sune, "Fabrication of Silicon Point, Wedge, and Trench FEAs", Technical Digest of IVMC 91, Nagahama 1991, pp. 34-35.
AK	DD		Millman, J. et al., Integrated Electronics: Analog and Digital Circuits and System, pp. 204-205, 1972 (no month).

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication with applicant.

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**U.S. PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Name	Class	Subclass	
<del>1/12/01</del>	AT	4,943,343	07/24/90	Bardai et al.	156	643
<del>1/12/01</del>	AU	4,874,981	10/17/89	Spindt	313	309
<del>1/12/01</del>	AV	4,766,340	08/23/88	van der Mast et al.	313	366
<del>1/12/01</del>	AW	4,718,973	01/12/88	Abraham et al.	156	628
<del>1/12/01</del>	AX	4,420,872	12/20/83	Solo de Zaldivar	029	571
<del>1/12/01</del>	AY	4,400,866	08/30/83	Yeh et al.	029	571
<del>1/12/01</del>	AZ	4,301,429	11/17/81	Goldman et al	333	022R
<del>1/12/01</del>	BA	3,970,887	07/20/76	Smith et al.	313	309
<del>1/12/01</del>	BB	3,894,332	07/15/75	Nathanson et al.	029	578
<del>1/12/01</del>	BC	3,875,442	04/01/75	Wasa et al.	313	193
<del>1/12/01</del>	BD	3,816,194	06/11/74	Kroger et al.	156	003
<del>1/12/01</del>	BE	3,812,559	05/28/74	Spindt et al.	029	25.18
<del>1/12/01</del>	BF	3,755,704	08/28/73	Spindt et al.	313	309
<del>1/12/01</del>	BG	3,665,241	05/23/72	Spindt et al.	313	351

**FOREIGN PATENT DOCUMENTS**

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